

ABSTRACT

A patch mechanism is described, which can be used to detect and workaround defects and conditions existing in an integrated circuit chip. The patch mechanism includes a trigger-matching logic incorporated within an integrated circuit chip to capture an incoming request cycle and determine if the captured incoming cycle matches one or more of trigger conditions. The patch mechanism further includes a control logic coupled to the trigger-matching logic to select a set of instructions upon detection of at least one matched trigger condition and to execute operations corresponding to the selected set of instructions. The control logic is configured to select the set of instructions based on the at least one matched trigger condition.